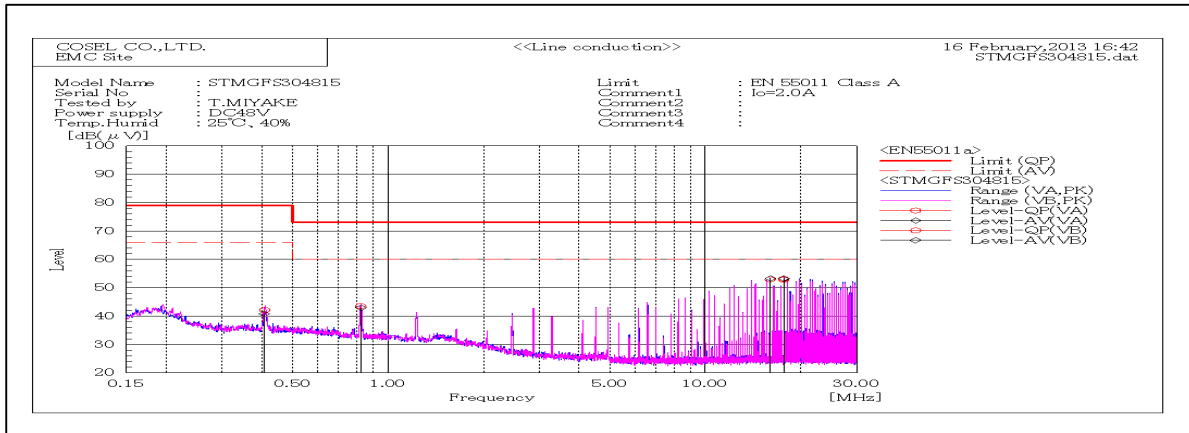
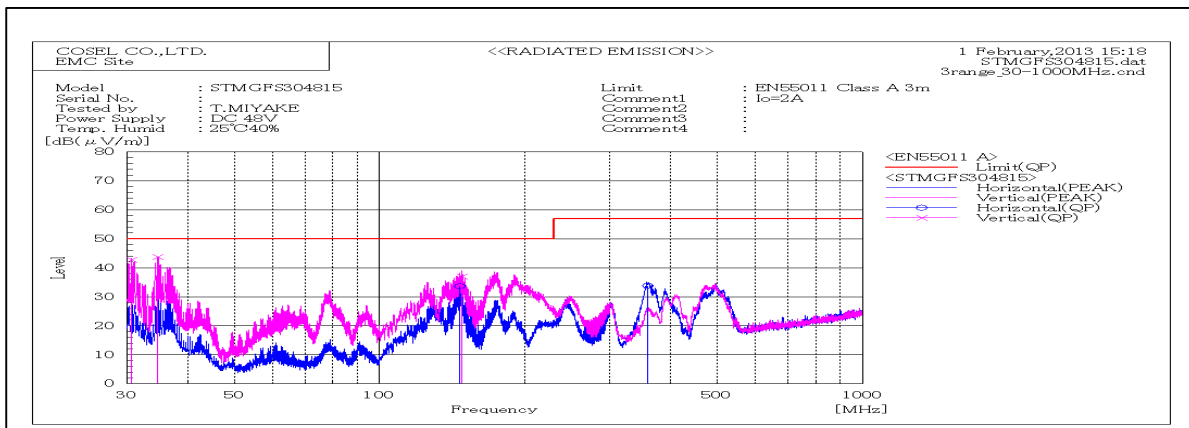


DATA SHEET		Date	18-Feb-13
Model	STMGFS304815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



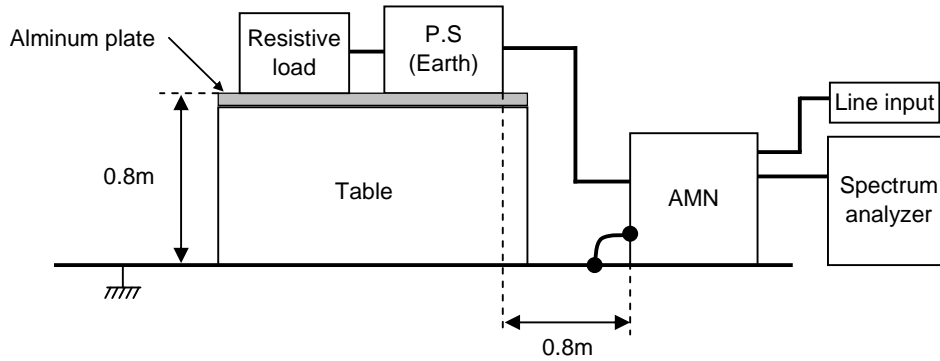
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.4091		VB	22.1	20.7	20.1	42.2	40.8	79	66	36.8	25.2	Pass	
0.82005		VA	23.4	23.4	20.1	43.5	43	73	60	29.5	17	Pass	
16.01045		VB	31.9	31.9	21	52.9	53.3	73	60	20.1	6.7	Pass	
17.6525		VB	31.7	31.7	21.1	52.8	53.2	73	60	20.2	6.8	Pass	
17.65075		VA	31.9	31.9	21.2	53.1	53.4	73	60	19.9	6.6	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP						
30.642	V	Stable	56.3		-13.6	42.7	50	7.3	Pass	101	215		
34.727	V	Stable	58.6		-14.8	43.8	50	6.2	Pass	101	185		
146.693	H	Stable	54		-20.3	33.7	50	16.3	Pass	158	256		
148.318	V	Stable	54.8		-17.8	37	50	13	Pass	104	299		
359.577	H	Stable	46.7		-12.9	33.8	57	23.2	Pass	103	69		

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

